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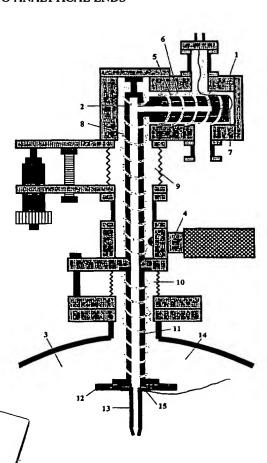
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[Continued on next page]

(54) Title: METHOD AND APPARATUS FOR IN SITU DEPOSITING OF NEUTRAL CS UNDER ULTRA-HIGH VACUUM TO ANALYTICAL ENDS



(57) Abstract: The present invention relates to a method for modifying the electronic properties of a surface to analytical ends, such as SIMS or electron spectroscopy, characterised in that it comprises in situ deposition of pure neutral cesium (Cso), under ultra-high vacuum, said neutral cesium being enabled in the form of a collimated adjustable stream. The invention relates also to the special column designed for implementing the method and to the corresponding energy and/or mass analyser instrument. ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PT, RO, SE, SI, SK, TR), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).

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INTERNATIONAL SEARCH REPORT

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According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal, WPI Data

Category °	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to daim No.
X ·	T. WIRTZ, B. DUEZ, HN. MIGEON, H. SCHERRER: "Useful yields of MCs+ and MCs2+ clusters: acomparative study between the Cameca IMS 4f and the Cation Mass Spectrometer" INTERNATIONAL JOURNAL OF MASS SPECTROMETRY, vol. 209, 2001, pages 57-67, XP001197305 cited in the application page 58, left-hand column, line 19 - right-hand column, line 22 page 66, right-hand column, last	1,3,4, 8-12,14, 15,17,18
,	paragraph; figure 1	

X Further documents are listed in the continuation of box C.	Patent family members are listed in annex.
Special categories of cited documents: A* document defining the general state of the art which is not considered to be of particular relevance E* earlier document but published on or after the international filing date L* document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified) O* document referring to an oral disclosure, use, exhibition or other means P* document published prior to the international filing date but tater than the priority date claimed	 "T" later document published after the International filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention "X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone "Y" document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art. "&" document member of the same patent family Date of mailing of the international search report
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European Patent Office, P.B. 5818 Patentlaan 2 NL – 2280 HV Rijswijk Tel. (+31-70) 340-2040, Tx. 31 651 epo nl, Fax: (+31-70) 340-3016	Wulveryck, J-M

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